

## 12.119 Problem Set: Electron Microprobe

### Question 1: Characteristic X-rays

For the following elements decide which one of the three diffracting crystals would be the best to measure the X-ray intensities of MgK $\alpha$ , CaK $\alpha$  and FeK $\alpha$ . The optimal range of  $2\theta$  for each crystal is between  $30^\circ$  and  $130^\circ$  and the best peak shape is achieved closest to the middle of the  $2\theta$  range of the spectrometer. Recall Bragg's Law,  $n\lambda = 2d\sin\theta$ . We are typically interested in first order diffractions (i.e.,  $n=1$ ).

Diffracting Crystal	Lattice spacing (2d) (nm)
TAP	2.5757
PET	0.8742
LiF	0.4027

  

Element	K $\alpha$ X-ray wavelength ( $\lambda$ ) (nm)
Mg	0.989
Ca	0.33584
Fe	0.193735

### Question 2: Quantitative analysis using Bence-Albee corrections

The X-ray intensity generated for an element “i” is proportional to the concentration ( $C_i$ ) of that element in the sample. However, the X-ray intensity emitted ( $I_i$ ) is different from the generated intensity because of the effects of average atomic number ( $Z$ ), absorption ( $A$ ) and fluorescence ( $F$ ) arising from the presence of other elements in the sample and the standard. This is known as the matrix effect. The emitted intensity ( $I_i$ ), concentration ( $C_i$ ) and matrix correction factors ( $ZAF$ ) are related by the following equation:

$$C_i^{\text{unk}} / C_i^{\text{std}} = (I_i^{\text{unk}} / I_i^{\text{std}}) * ZAF \quad (1)$$

where, “unk,” denotes the unknown compound, “std,” the standard, and  $I_i^{\text{unk}} / I_i^{\text{std}}$ , the X-ray intensity ratio, is known as the “k-ratio” of element i ( $k_i$ ):

$$k_i = I_i^{\text{unk}} / I_i^{\text{std}} \quad (2)$$

$ZAF$  includes the combined effects of the matrices of the unknown and the standard. Since the standard composition is known, the contribution to  $ZAF$  from the standard is also known. The concentration in the standard divided by its own matrix correction factors is the standard correction factor ( $CF$ ). The contribution to  $ZAF$  from the unknown is denoted by  $\beta$ . Hence, for element i in the unknown compound with n elements:

$$C_i = \beta_i k_i CF_i \quad (3)$$

where,

$$\beta_i = (C_1\alpha_{i1} + C_2\alpha_{i2} + \dots + C_i\alpha_{ii} + \dots + C_n\alpha_{in}) / (C_1 + C_2 + \dots + C_i + \dots + C_n) \quad (4)$$

where,  $\alpha_{ij}$  is the  $\alpha$ -factor, a constant for element  $i$  in the binary system  $i$ - $j$ , at a given value of electron beam energy  $E_0$  and take-off angle  $\psi$ . The value of  $\alpha_{ii}$ , which is the  $\alpha$ -factor of element  $i$  in itself, is unity.

Since both  $C_i$  and  $\beta_i$  are unknown in the above equations, an iterative procedure is used to determine  $C_i$ . In the first step, an initial “first approximation” concentration of each element is calculated as:

$$C_i^0 = k_i CF_i \quad (5)$$

Using these “first approximation” concentrations, the initial values of  $\beta$  are calculated as:

$$\beta_i^0 = (C_1^0 \alpha_{i1} + C_2^0 \alpha_{i2} + \dots + C_i^0 \alpha_{ii} + \dots + C_n^0 \alpha_{in}) / (C_1^0 + C_2^0 + \dots + C_i^0 + \dots + C_n^0) \quad (6)$$

Then, the next set of concentrations is calculated using the  $\beta^0$  values and equation (3). In turn, the next set of  $\beta$  values are calculated using equation (6). This procedure is repeated until the differences between successive calculated  $\beta$  values are arbitrarily small. This happens after 3 or 4 iterations. The final calculated concentrations are determined using equation (3) and the final calculated  $\beta$  values.

In the following problem, the measured (emitted) X-ray intensities of Mg, Si and Fe in standards and an olivine sample are given. *Synthetic forsterite* for Mg and Si, and *Marjalotti olivine* for Fe were used as standards. Although we measure the intensities of the elements, the Bence-Albee correction procedure calculates the concentrations as oxides because the standard composition is defined in terms of oxides. The  $\alpha$ -factors at  $E_0=15$  keV and  $\psi=40^\circ$  are provided. Calculate the concentrations of MgO, SiO<sub>2</sub> and FeO in the sample using the iterative procedure discussed above (repeat up to 4 iterations).

	<u>MgO</u>	<u>SiO<sub>2</sub></u>	<u>FeO</u>	<u>comment</u>
$I_i^{std}$	393.46	328.81	22.1	standard intensity
<b>CF</b>	0.5473	0.3364	0.1018	standard correction factor
$I_i^{unk}$	329.72	325.26	14.51	measured intensity in the sample
$\alpha_{Mg-i}$	1	1.085	2.101	alpha factors: $\alpha_{Mg-Mg}$ , $\alpha_{Mg-Si}$ , $\alpha_{Mg-Fe}$
$\alpha_{Si-i}$	1.414	1	1.3	alpha factors: $\alpha_{Si-Mg}$ , $\alpha_{Si-Si}$ , $\alpha_{Si-Fe}$
$\alpha_{Fe-i}$	1.119	1.126	1	alpha factors: $\alpha_{Fe-Mg}$ , $\alpha_{Fe-Si}$ , $\alpha_{Fe-Fe}$
$k_i$	...	...	...	k-ratio
$C_i^0$	...	...	...	“first approximation” concentration
$\beta_i^0$	...	...	...	first $\beta$
$C_i^1$	...	...	...	concentration after first iteration
$\beta_i^1$	...	...	...	$\beta$ after first iteration
...	...	...	...	successive iterations
$C_i$	...	...	...	final concentration

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